FIG. 1

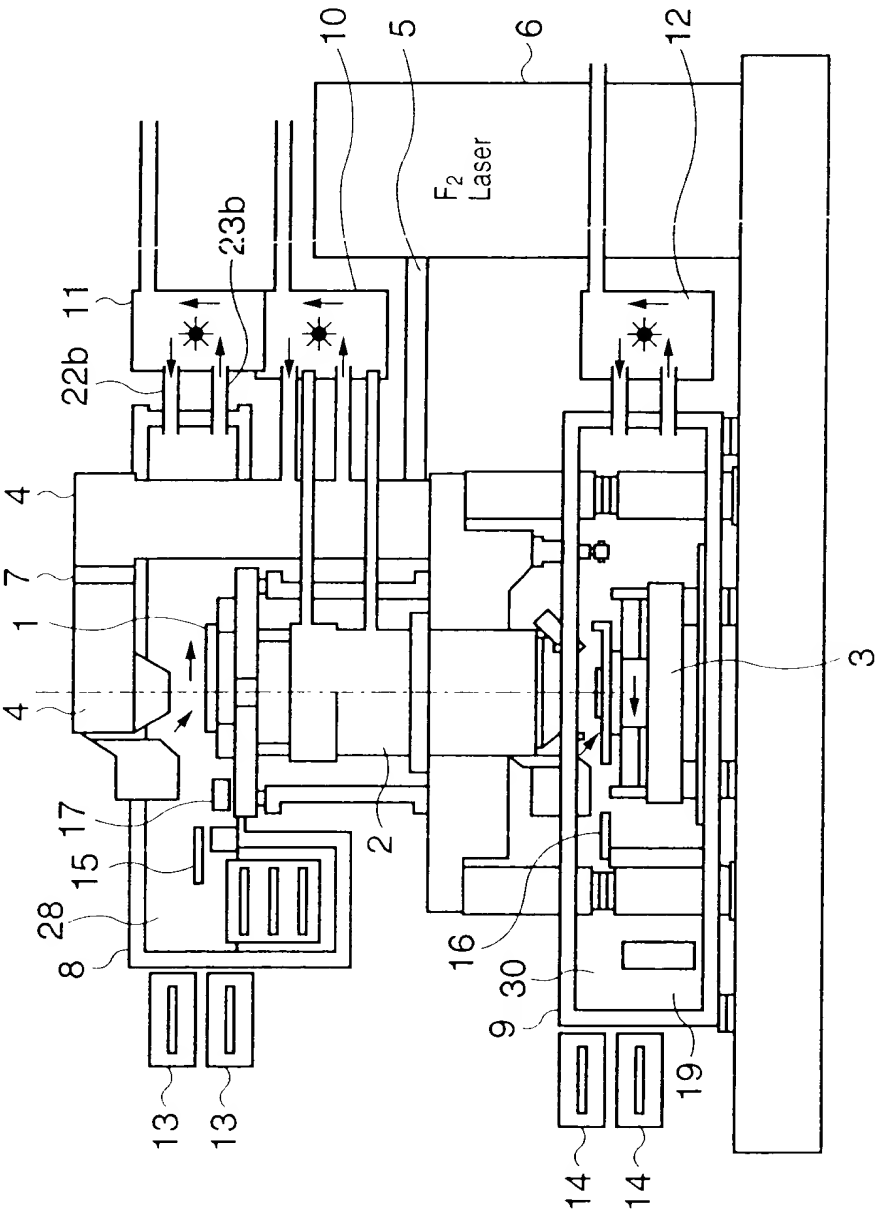


FIG. 2

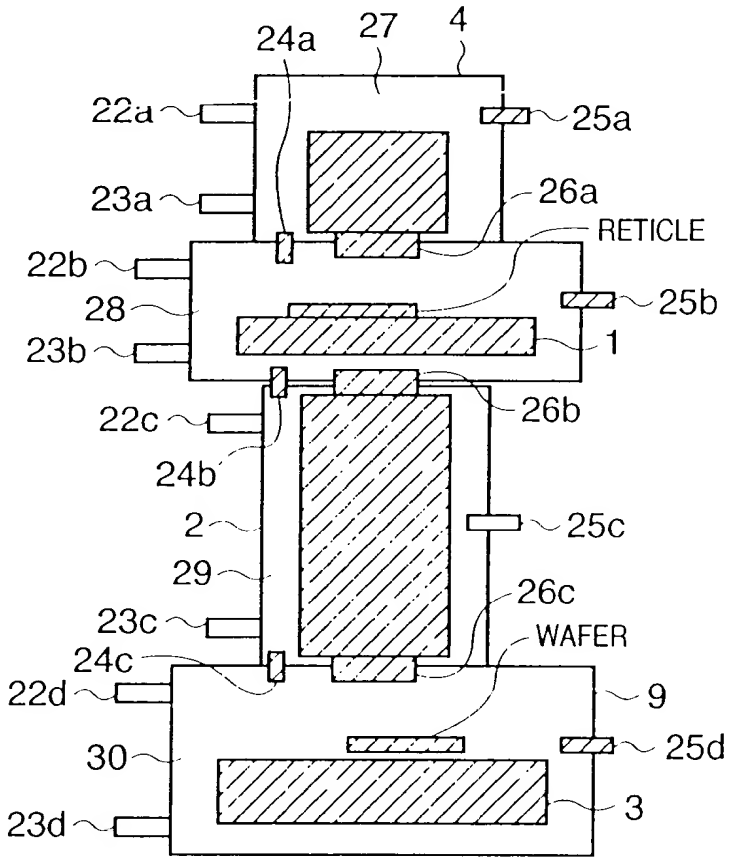

24a
27
4
22a
25a
23a
26a
RETICLE
22b
28
25b
23b
1
26b
22c
24b
2
25c
29
26c
23c
WAFER
24c
22d
9
30
25d
23d
3

FIG. 3

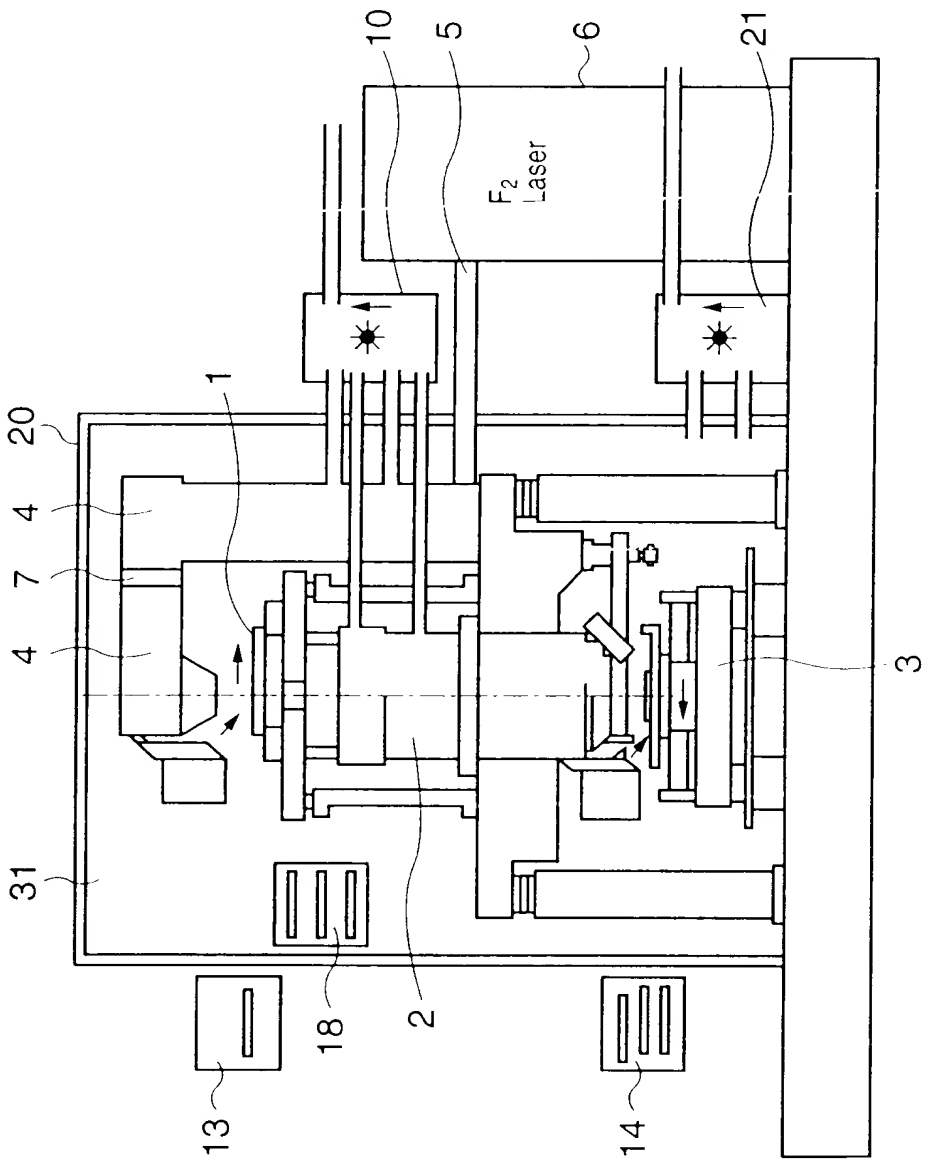
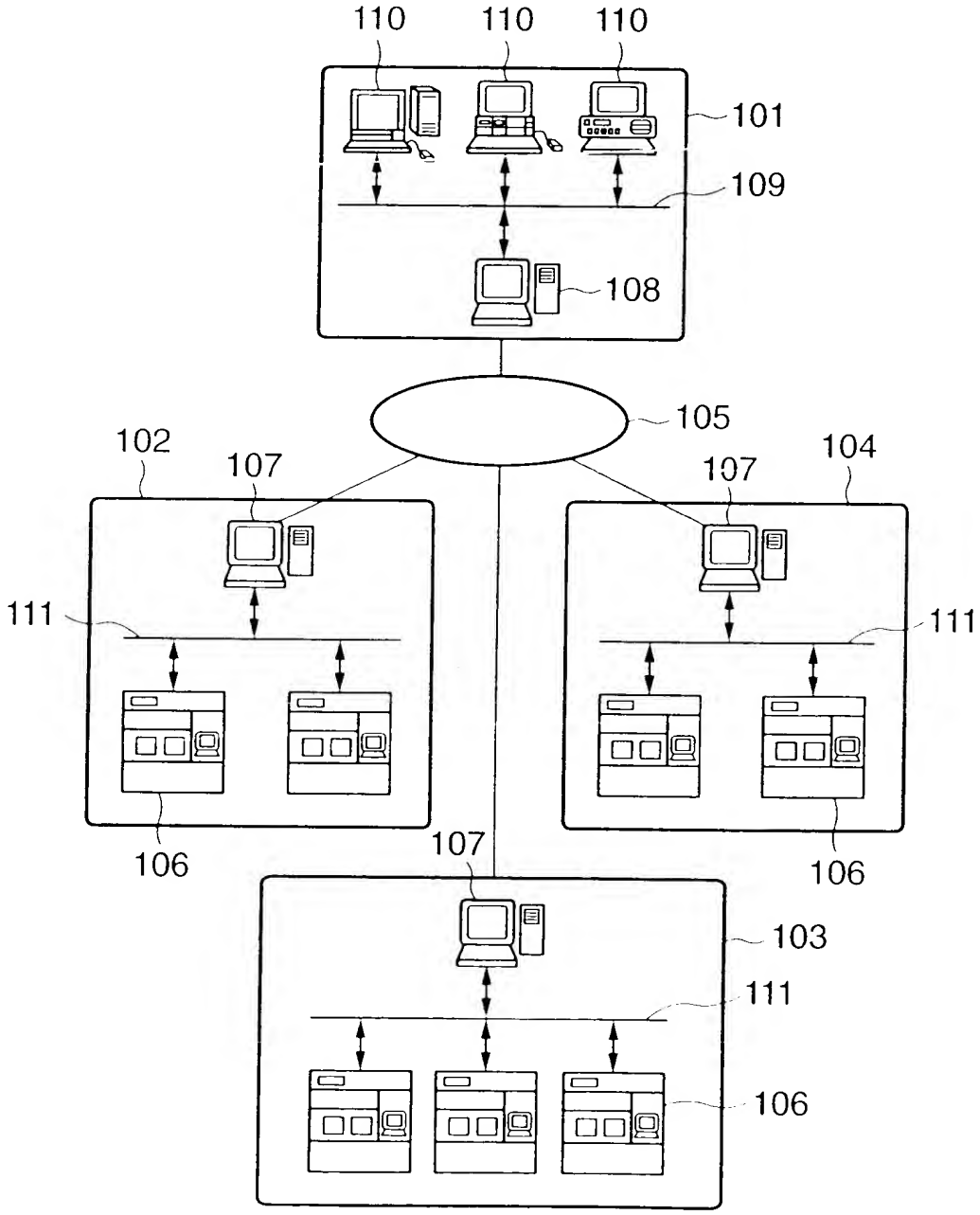


FIG. 4


110
110
110
101
109
108
105
102
107
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107
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111
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107
106
103
111
106

FIG. 5

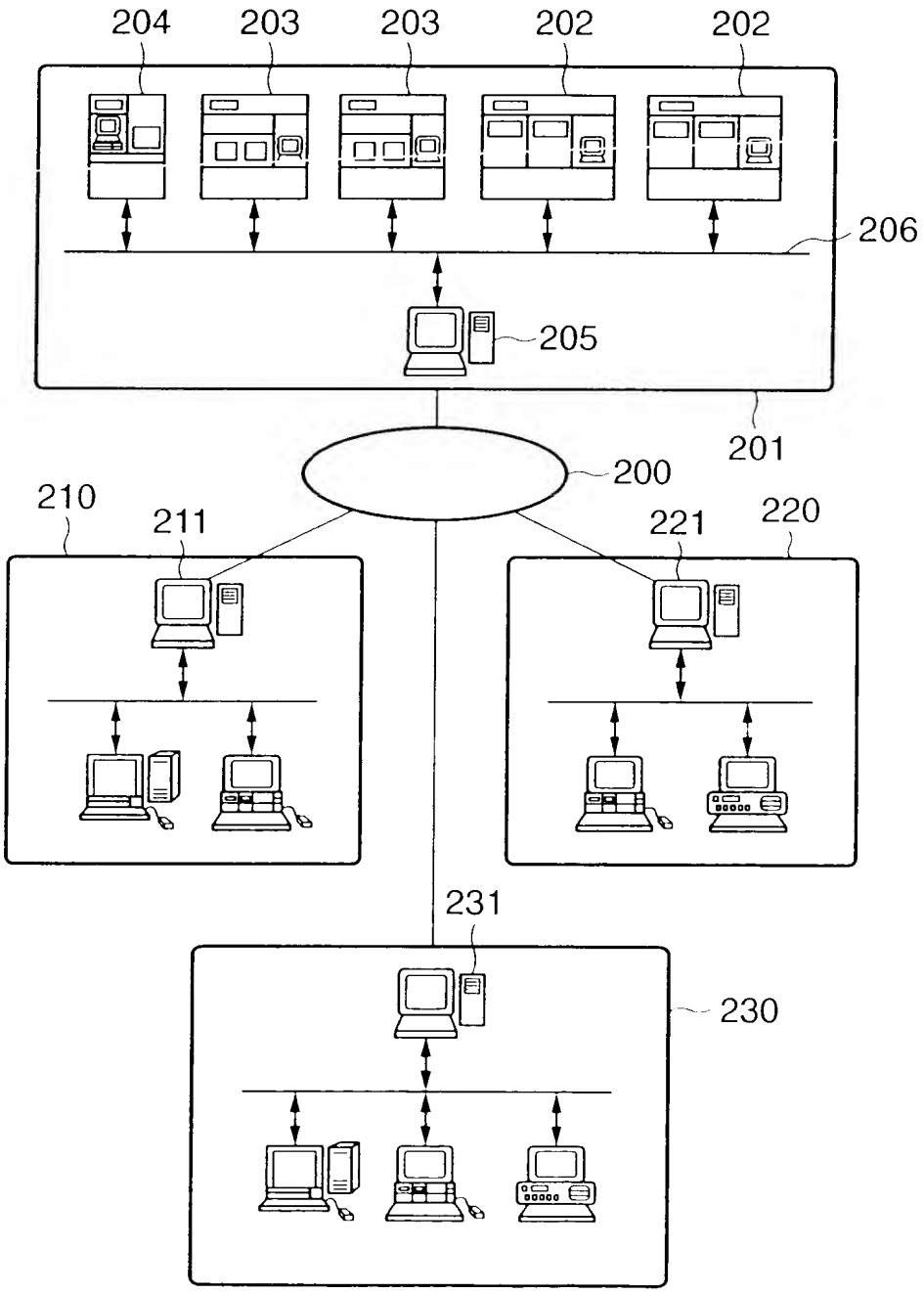


FIG. 6

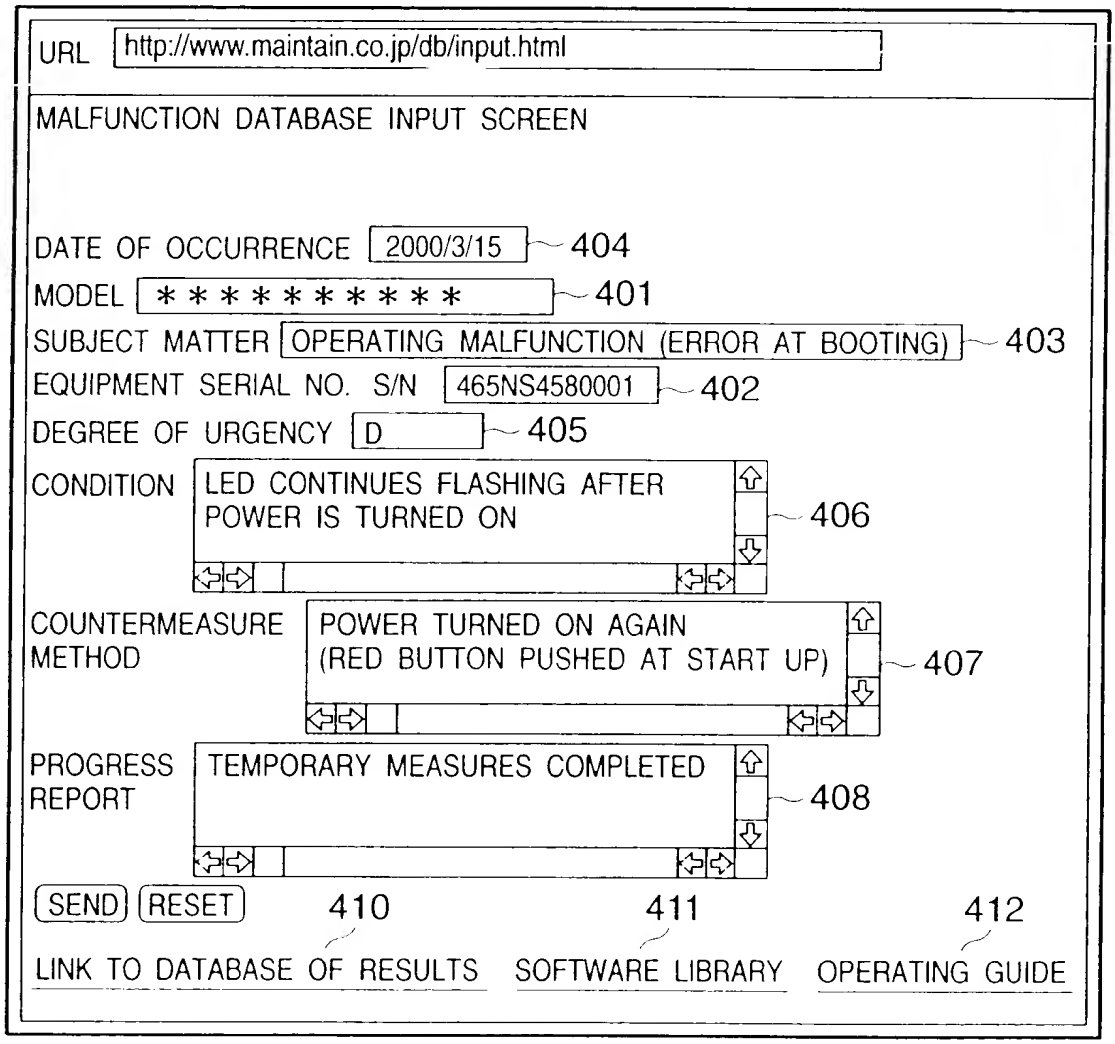
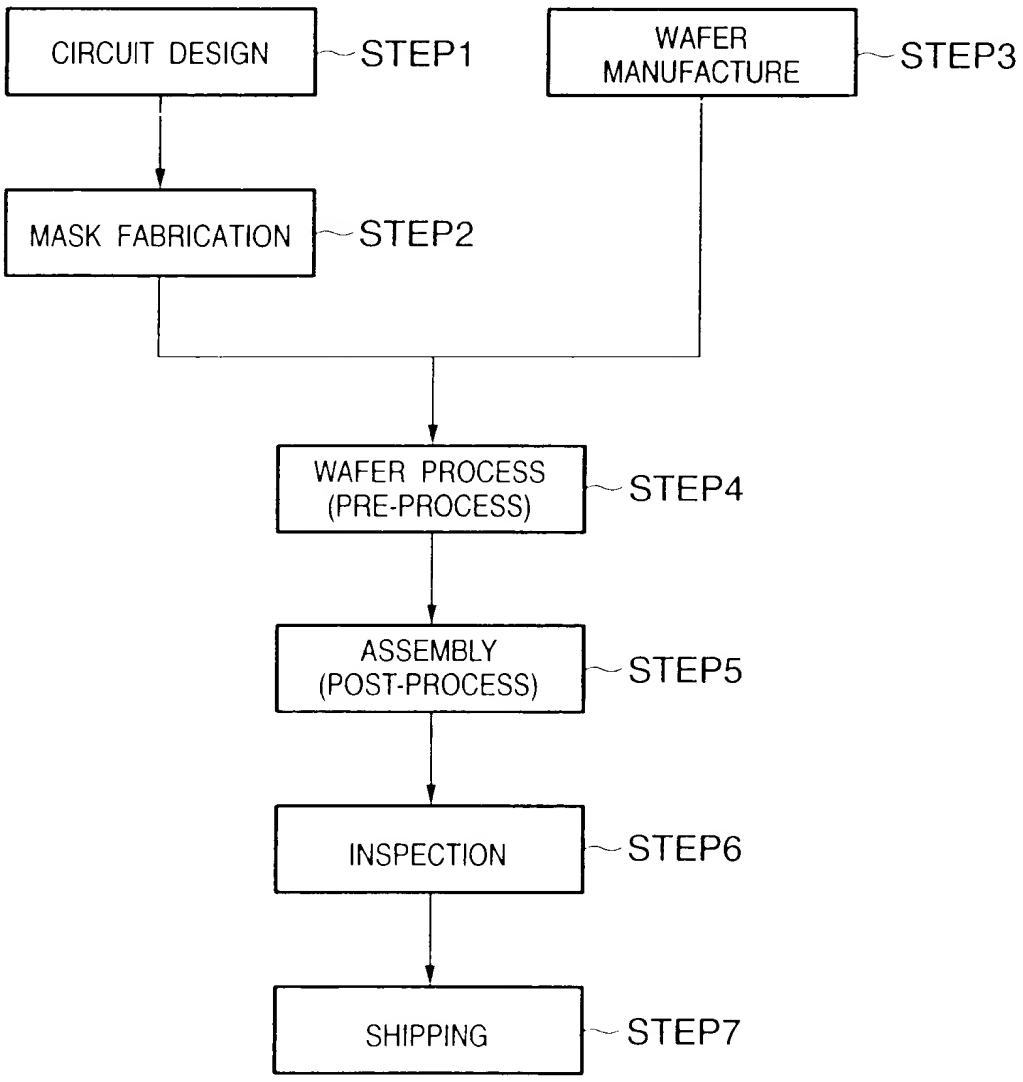
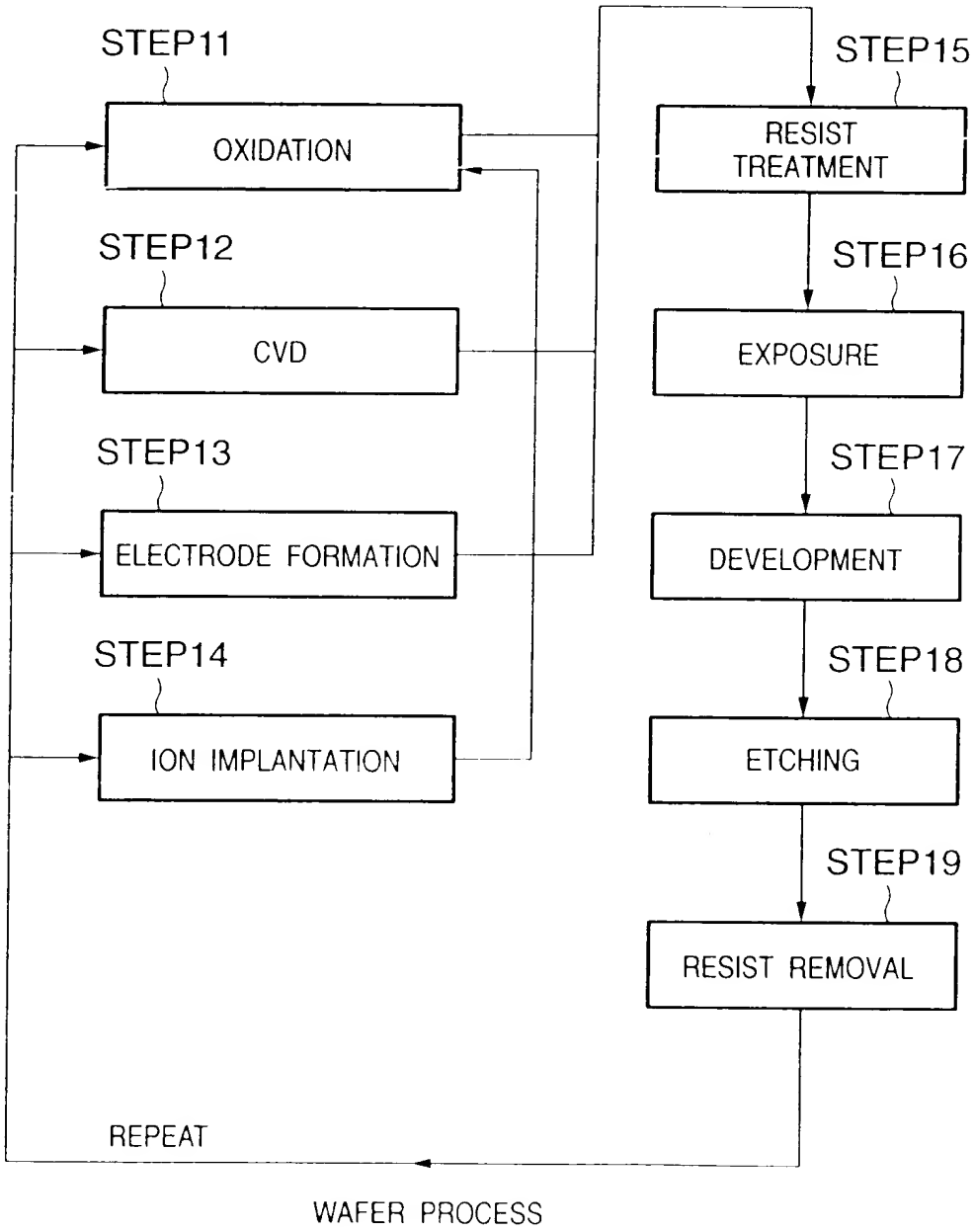

URL
http://www.maintain.co.jp/db/input.html
MALFUNCTION DATABASE INPUT SCREEN
DATE OF OCCURRENCE
2000/3/15
404
MODEL
****
401
SUBJECT MATTER
OPERATING MALFUNCTION (ERROR AT BOOTING)
403
EQUIPMENT SERIAL NO. S/N
465NS4580001
402
DEGREE OF URGENCY
D
405
CONDITION
LED CONTINUES FLASHING AFTER POWER IS TURNED ON
406
COUNTERMEASURE METHOD
POWER TURNED ON AGAIN (RED BUTTON PUSHED AT START UP)
407
PROGRESS REPORT
TEMPORARY MEASURES COMPLETED
408
SEND
RESET
410
411
412
LINK TO DATABASE OF RESULTS
SOFTWARE LIBRARY
OPERATING GUIDE

FIG. 7



SEMICONDUCTOR DEVICE MANUFACTURING FLOW

FIG. 8


STEP11
OXIDATION
STEP12
CVD
STEP13
ELECTRODE FORMATION
STEP14
ION IMPLANTATION
STEP15
RESIST TREATMENT
STEP16
EXPOSURE
STEP17
DEVELOPMENT
STEP18
ETCHING
STEP19
RESIST REMOVAL
REPEAT
WAFER PROCESS